Electronic Supplementary Material (ESI) for Journal of Materials Chemistry C.

Supplementary Information

Figures and Tables captions

Figure S1 – Diffuse reflectance infrared Fourier transform (DRIFT) spectra of Eu(tta)$_3$ephen (black line), MCM matrix (blue line) and the **MCM-Eu** sample (red line)

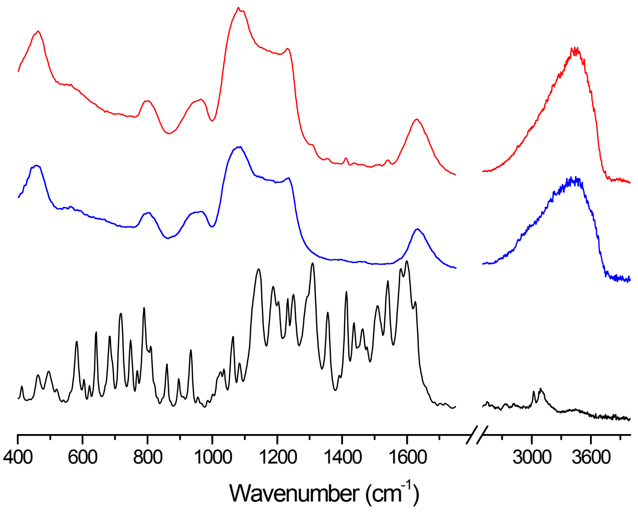

Figure S2 – Emission decay curves excited at 275 and 375 nm and monitored at 612 nm of **MCM-Eu**. The insets show the residual plot resulting from the fit procedure.